Issue Classification	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/003,653	YAMADA ET AL.	
	Examiner	**Art Unit**	
	Christina Y. Leung	2633	

ISSUE CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)						
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
398	50	398	48					

INTERNATIONAL CLASSIFICATION													
H	0	4	J	14/00									
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				/									
				/									

Christina Y Leung 5-16-05
(Assistant Examiner) (Date)

(Legal Instruments Examiner) (Date) 5/18/05

JASON CHAN
SUPERVISORY PATENT EXAMINER
TECHNOLOGY CENTER 2600
(Primary Examiner) (Date)

Total Claims Allowed: 4

O.G. Print Claim(s)	O.G. Print Fig.
1	1

☐ Claims renumbered in the same order as presented by applicant ☐ CPA ☐ T.D. ☐ R.1.47

Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
1	1		31		61		91		121		151		181
	2		32		62		92		122		152		182
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	4		34		64		94		124		154		184
	5		35		65		95		125		155		185
	6		36		66		96		126		156		186
	7		37		67		97		127		157		187
	8		38		68		98		128		158		188
	9		39		69		99		129		159		189
	10		40		70		100		130		160		190
2	11		41		71		101		131		161		191
3	12		42		72		102		132		162		192
4	13		43		73		103		133		163		193
	14		44		74		104		134		164		194
	15		45		75		105		135		165		195
	16		46		76		106		136		166		196
	17		47		77		107		137		167		197
	18		48		78		108		138		168		198
	19		49		79		109		139		169		199
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	25		55		85		115		145		175		205
	26		56		86		116		146		176		206
	27		57		87		117		147		177		207
	28		58		88		118		148		178		208
	29		59		89		119		149		179		209
	30		60		90		120		150		180		210

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